

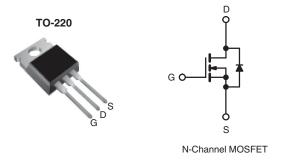
RoHS

COMPLIANT



Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	60			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.018		
Q _g (Max.) (nC)	110			
Q _{gs} (nC)	29			
Q _{gd} (nC)	36			
Configuration	Single			



FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- Ultra Low On-Resistance
- · Very Low Thermal Resistance
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRFZ48PbF
	SiHFZ48-E3
SnPb	IRFZ48
	SiHFZ48

ABSOLUTE MAXIMUM RATINGS T	$_{\rm C}$ = 25 $^{\circ}$ C, unless otherw	vise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	60	V	
Gate-Source Voltage	V_{GS}	± 20			
Continuous Drain Current ^e	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		50	А	
	$T_C = 100 ^{\circ}$ C	ID	50		
Pulsed Drain Current ^a	I _{DM}	290			
Linear Derating Factor			1.3	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	100	mJ	
Avalanche Current ^a	I _{AR}	50	Α		
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ		
Maximum Power Dissipation	T _C = 25 °C	P_{D}	190	W	
Peak Diode Recovery dV/dtc		dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature) ^d	for 10 s		300	7	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF WIS SCIEW		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 22 μ H, R_G = 25 Ω I_{AS} = 72 A (see fig. 12).
- c. $I_{SD} \le 72$ A, $dV/dt \le 200$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.
- d. 1.6 mm from case
- e. Current limited by the package, (die current = 72 A).
- * Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.80	

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static					•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	Reference to 25 °C, I _D = 1 mA		0.060	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{c}$	_{GS} , I _D = 250 μA	2.0	-	4.0	٧
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20		-	-	± 100	nA
Zava Cata Valtaga Dvain Current	1	V _{DS} = 60 V, V _{GS} = 0 V		-	-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 48 V, V ₀	_{GS} = 0 V, T _J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 43 A ^b	-	-	0.018	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 25 V, I _D = 43 A ^b		27	-	-	S
Dynamic		<u>.</u>					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	2400	-	pF
Output Capacitance	C _{oss}			-	1300	-	
Reverse Transfer Capacitance	C _{rss}			-	190	-	
Total Gate Charge	Qg		V _{GS} = 10 V	-	-	110	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	29	
Gate-Drain Charge	Q _{gd}		See lig. o and 10	-	-	36	
Turn-On Delay Time	t _{d(on)}			-	8.1	-	
Rise Time	t _r	\/ 2	0 V I 72 A	-	250	-	
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 30 \text{ V, } I_D = 72 \text{ A,}$ $R_G = 9.1 \Omega, R_D = 0.34 \Omega, \text{ see fig. } 10^b$		-	210	-	ns
Fall Time	t _f			-	250	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	الم
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		ı	-	50°	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	290	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 72 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	2.0	٧
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 72 A, dl/dt = 100 A/μs ^b		-	120	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.50	0.80	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S an				y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.
- c. Current limited by the package, (die current = 72 A).



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

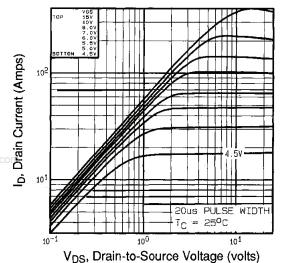


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

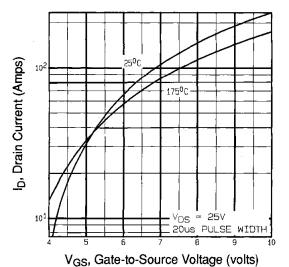


Fig. 3 - Typical Transfer Characteristics

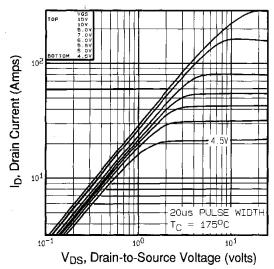


Fig. 2 - Typical Output Characteristics, $T_C = 175$ °C

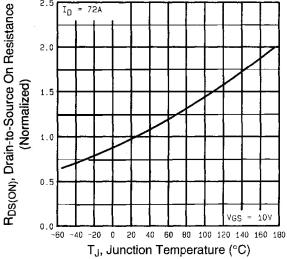


Fig. 4 - Normalized On-Resistance vs. Temperature

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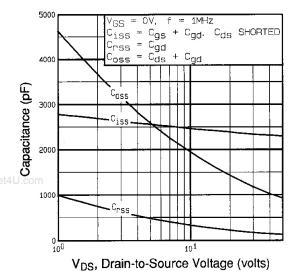


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

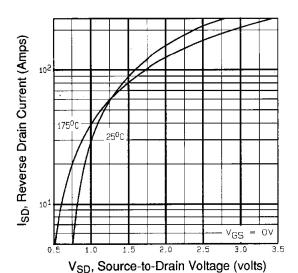


Fig. 7 - Typical Source-Drain Diode Forward Voltage

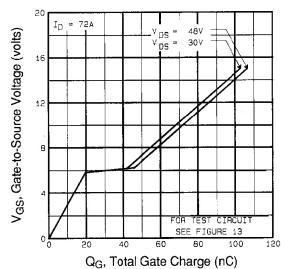


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

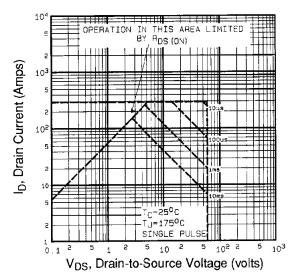


Fig. 8 - Maximum Safe Operating Area





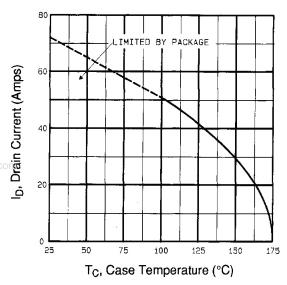


Fig. 9 - Maximum Drain Current vs. Case Temperature

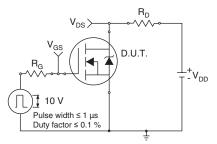


Fig. 10a - Switching Time Test Circuit

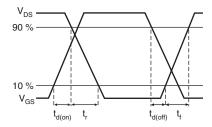


Fig. 10b - Switching Time Waveforms

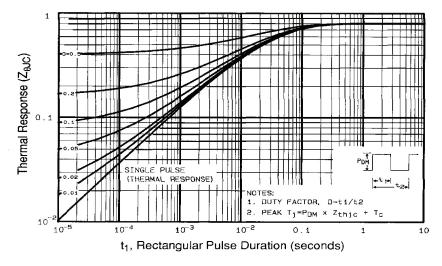


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

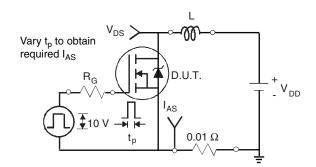


Fig. 12a - Unclamped Inductive Test Circuit

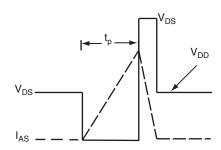


Fig. 12b - Unclamped Inductive Waveforms

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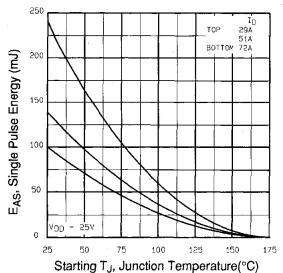


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

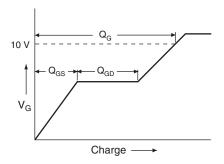


Fig. 13a - Basic Gate Charge Waveform

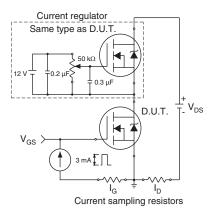
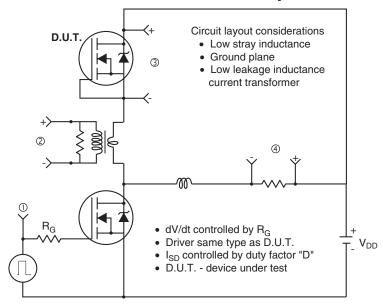
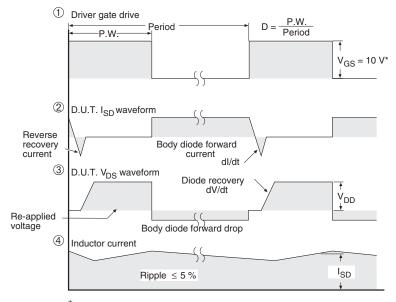


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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